



P.O. BOX 265
OGDENSBURG, NY
U.S.A. 13669-0265

TEL: 888-670-8729 (USA & Canada) or +1-613-686-6675 (Intl)
FAX: 800-561-1970 (USA & Canada) or +1-613-686-6679 (Intl)

BOX 5120, LCD MERIVALE
OTTAWA, ONTARIO
CANADA K2C 3H4

info@avtechpulse.com - http://www.avtechpulse.com/

PERFORMANCE CHECKSHEET

Model: AVR-EB4-B
Type: Semiconductor Device Tester
S.N.: 12232
Date: March 16, 2009

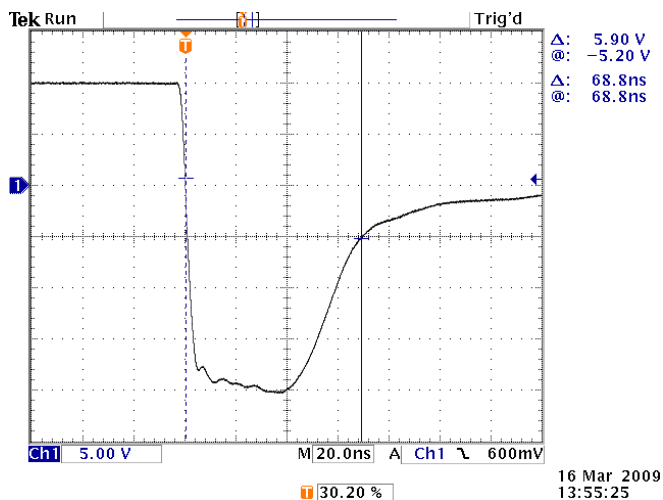
Output Amplitude: to +2A, -4A
Pulse Width (FWHM): 2 – 20 us
Switching Time,
+ to -, 10%-90%: ≤ 4.5 ns
PRF: 1 - 100 Hz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

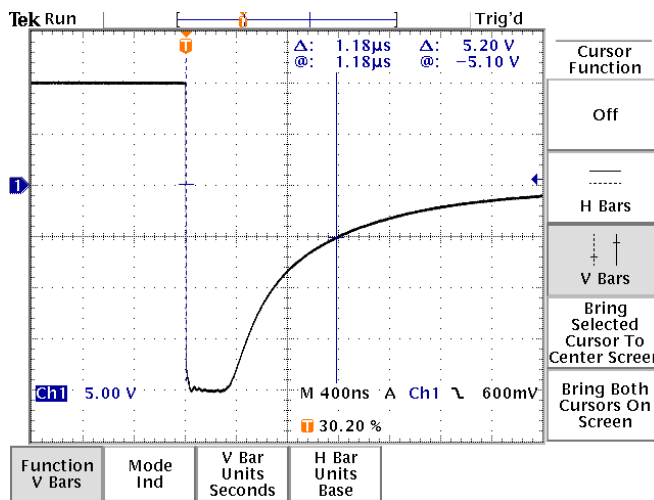
Test Waveforms

With an On Semi 1N4937 installed in the AVX-TRR-MIX test jig, connected using the 24" coaxial cable:

With a generic 1N4004 installed in the AVX-TRR-MIX test jig, connected using the 24" coaxial cable:

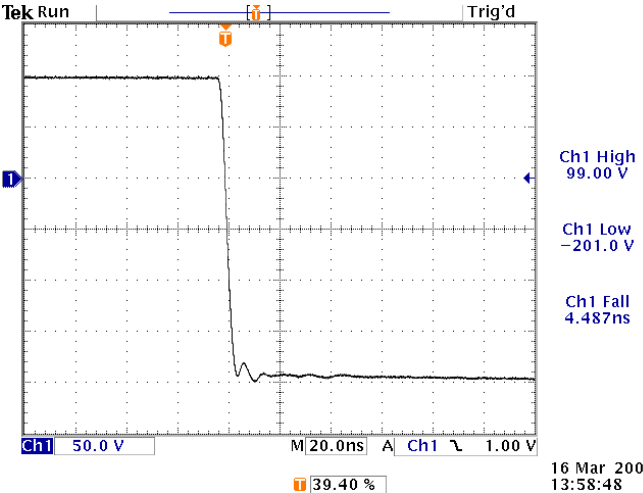


$I_F = +2A, I_R = -4A, I_{RR} = -1A.$
100 Hz, 20 us PW.
5V (1A) / div, 20 ns/div.
Measured $t_{RR} = 68.8$ ns.



$I_F = +2A, I_R = -4A, I_{RR} = -1A.$
100 Hz, 20 us PW.
5V (1A) / div, 400 ns/div.
Measured $t_{RR} = 1.18$ us.

Mainframe output, into 50 Ohms:



50 V / div, 20 ns/div. +100V, -200V.

10% - 90% fall time shown.